

| | | | | |
|-----------------------------------|--|---------------------------------------|--|-------------|
| Notice of References Cited | | Application/Control No. 10/588,346 | Applicant(s)/Patent Under Reexamination SCHMIDT ET AL. | |
| | | Examiner DEVE VALDEZ | Art Unit 4151 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|--|-----------------|----------------------|----------------|
| * | A US-5,716,679 | 02-1998 | Krug et al. | 427/515 |
| * | B US-5,334,631 | 08-1994 | Durand, Dominique | 523/459 |
| * | C US-2004/0178530 | 09-2004 | Yadav, Tapesh | 264/005 |
| * | D US-2008/0044651 | 02-2008 | Douglas, Joel S. | 428/339 |
| * | E US-2003/0087094 | 05-2003 | Smith et al. | 428/402 |
| * | F US-2004/0108628 | 06-2004 | Yadav et al. | 264/603 |
| * | G US-5,491,184 | 02-1996 | McBain et al. | 523/436 |
| * | H US-2008/0188605 | 08-2008 | Lubnin, Alexander V. | 524/432 |
| I | US- | | | |
| J | US- | | | |
| K | US- | | | |
| L | US- | | | |
| M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|--|-----------------|---------|------|----------------|
| N | | | | | |
| O | | | | | |
| P | | | | | |
| Q | | | | | |
| R | | | | | |
| S | | | | | |
| T | | | | | |

NON-PATENT DOCUMENTS

| * | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|--|
| U | Richard J. Lewis Sr., Hawley's Condensed Chemical Dictionary, 2001, John Wiley and Sons, 14th edition, P. 1029 and 286 |
| V | |
| W | |
| X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.